



SLOVENSKI STANDARD SIST EN IEC 62228-1:2018

01-september-2018

Integrirana vezja - Vrednotenje elektromagnetne združljivosti (EMC) oddajnikov-sprejemnikov - 1. del: Splošni pogoji in definicije (IEC 62228-1:2018)

Integrated Circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions (IEC 62228-1:2018)

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Ta slovenski standard je istoveten z: **EN IEC 62228-1:2018**
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ICS:

31.200	Integrirana vezja, mikroelektronika	Integrated circuits. Microelectronics
33.100.01	Elektromagnetna združljivost na splošno	Electromagnetic compatibility in general

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EUROPEAN STANDARD

EN IEC 62228-1

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2018

ICS 31.200

English Version

Integrated circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions (IEC 62228-1:2018)

Circuits intégrés - Évaluation CEM des émetteurs-
récepteurs - Partie 1 : Conditions générales et définitions
(IEC 62228-1:2018)

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von Sende-
Empfangsgeräten - Teil 1: Allgemeine Bedingungen und
Festlegungen
(IEC 62228-1:2018)

This European Standard was approved by CENELEC on 2018-02-13. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 62228-1:2018 (E)**European foreword**

The text of document 47A/1018/CDV, future edition 1 of IEC 62228-1, prepared by IEC/SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62228-1:2018.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-12-01
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2021-06-01

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The text of the International Standard IEC 62228-1:2018 was approved by CENELEC as a European Standard without any modification.

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-4	2002	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN 61967-4	2002
+ A1	2006		+ A1	2006
-	-		+ corrigendum Dec. 2006	2006
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity -- Part 3: Non-synchronous transient injection method	EN 62215-3	-
ISO 10605	-	Road vehicles - Test methods for electrical - disturbances from electrostatic discharge		-

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INTERNATIONAL STANDARD

**Integrated circuits – EMC evaluation of transceivers –
Part 1: General conditions and definitions**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS –
EMC evaluation of transceivers –**

Part 1: General conditions and definitions

FOREWORD

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International Standard IEC 62228-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

CDV	Report on voting
47A/1018/CDV	47A/1034/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.